

Changes in Field Failure Degradation Modes Over Time



Duramat Workshop

Stanford, CA

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Outline

- ❖ Definitions: failure - degradation
- ❖ Failure rates
- ❖ Degradation modes
- ❖ Changes in the last 10 years
- ❖ “New” degradation modes

Why study literature?

**Great overview of the aggregated knowledge of the PV community
but determination of trends from literature can be difficult:**

1. Unknown quality of modules/systems/installation
2. Many factors may influence failure/degradation modes and often they are not clearly documented
3. Inconsistent use of reporting terminology
4. Misidentification
5. Synergy of degradation modes: often multiple modes can be seen in single module/system

Failure ↔ Degradation

Definition of failure: IEC 60050-191

“Failure is the termination of the ability of an item to perform a required function”

What does that mean for PV module?

Failure ↔ Degradation

Definition of failure: IEC 60050-191

“Failure is the termination of the ability of an item to perform a required function”

What does that mean for PV module?

Several different definitions of PV “failures” have been used!!

1980: JPL Block Buy Program “failure < 75% of short-circuit current (I_{sc})

1993: EPRI: power decline > 50% that cannot be repaired in field

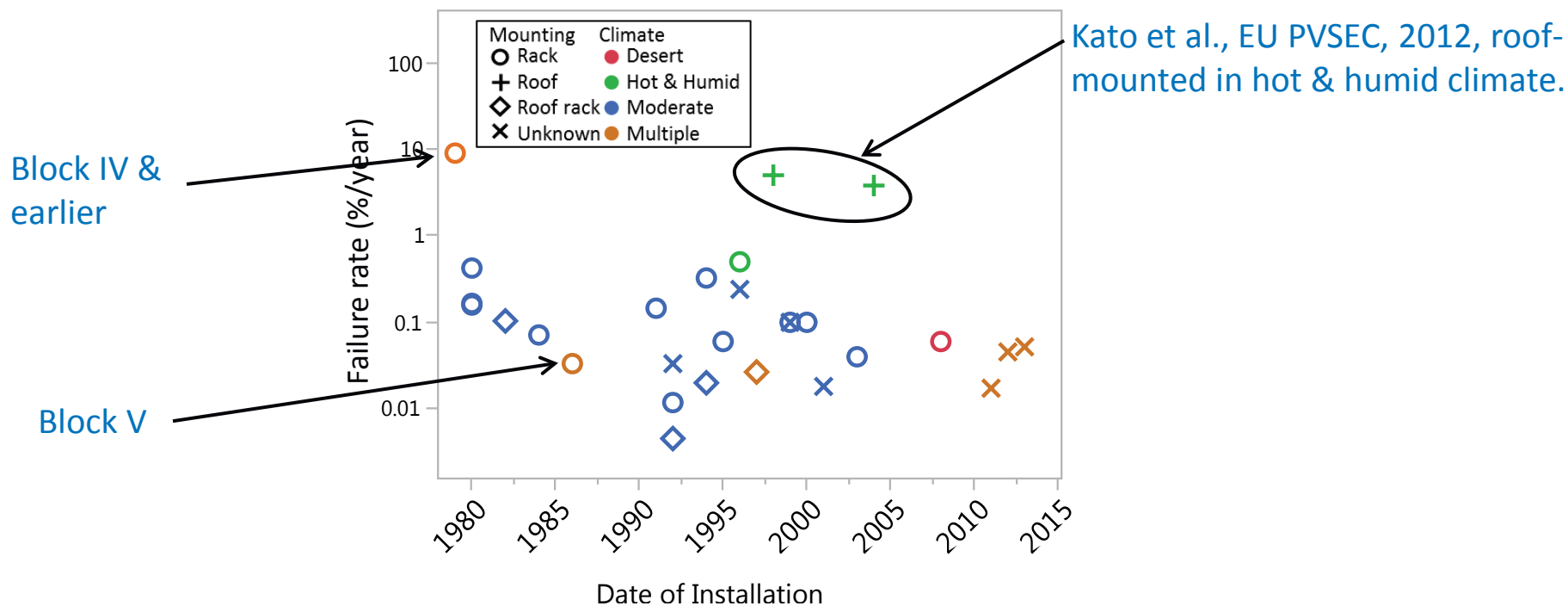
2014: IEA: modules undergoing irreversible changes

Maybe: Modules that default on warranty, which warranty?

Failure rates need to take into account field exposure

Failure rates are typically not reported, failure ratios are reported.

Define failure as modules that required replacement.



Expected failure rate 5 out of 10,000 modules annually

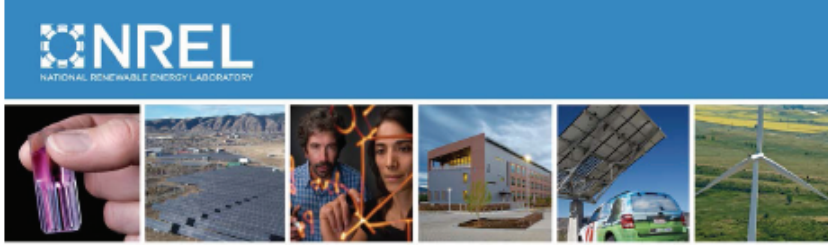
Visual Inspection Tool is not as widely used as we'd like

- Uses IEC/UL standard terminology
- Balance collection of sufficient detail for degradation mode evaluation against minimizing recording time per module
- Consists of 14 sections- based on module component
- Short & long version available

Example: front glass



Visual inspection could help discriminate between these cases



Development of a Visual Inspection Data Collection Tool for Evaluation of Fielded PV Module Condition

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NREL is a national laboratory of the U.S. Department of Energy, Office of Energy Efficiency & Renewable Energy, operated by the Alliance for Sustainable Energy, LLC.

Technical Report
NREL/TP-5200-56154
August 2012

Contract No. DE-AC36-08G028308

How can we be more quantitative?

Risk priority number (RPN) = No. reports * No. affected modules * Severity * Detectability

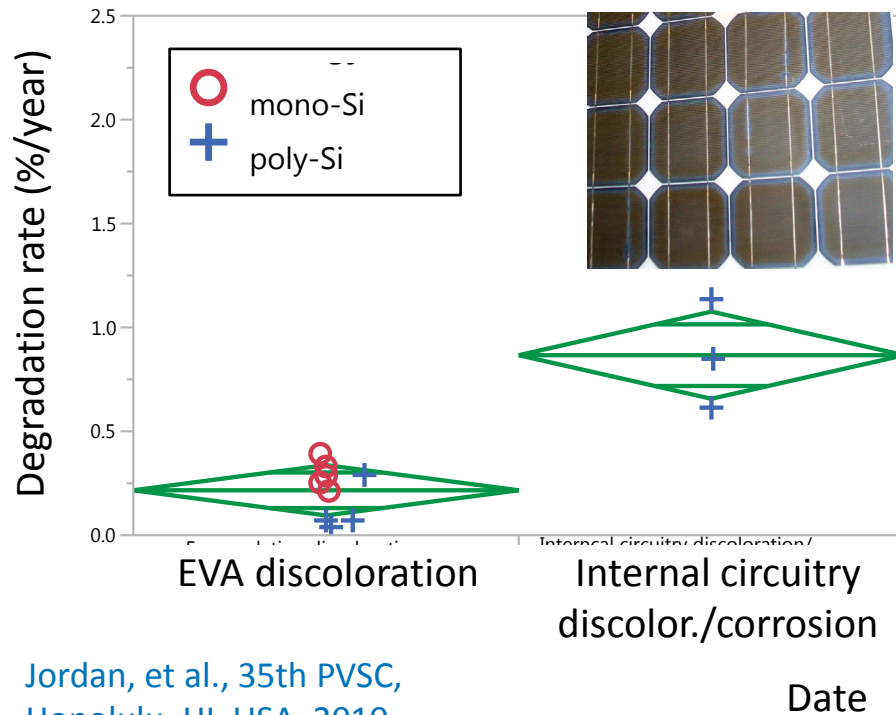
Severity	Rating
Major impact on power & safety	10
Major impact on power	8
Significant impact on power	5
Slight deterioration of performance	3
No effect on performance	1

For better discrimination the scale is not continuous

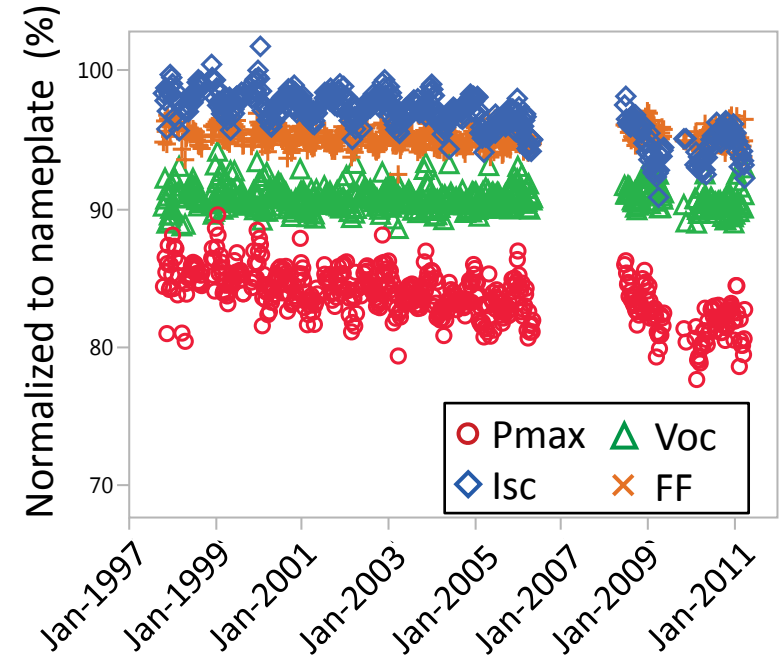
Mode	Severity
Backsheet insulation compromise	10
Hot spots	10
Internal circuitry (IC) failure	8
PID	8
Major delamination	5
Internal circuitry (IC) discoloration	5
Fractured Cells	5
Diode/J-box problem	5
Glass breakage	5
Encapsulant discoloration	3
Frame deformation	3
Permanent soiling	2
Minor delamination	1
Backsheet other	1

Synergy of degradation modes often make it difficult to determine the power impact of a specific degradation mode.

Encapsulation discoloration associated with small power loss



Jordan, et al., 35th PVSC,
 Honolulu, HI, USA, 2010.

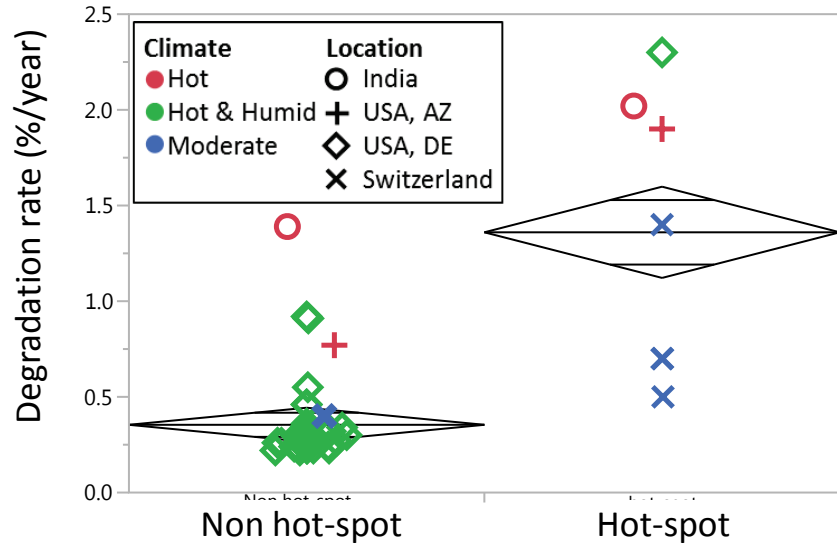


Encapsulant discoloration associated with lower power loss in direct comparison.

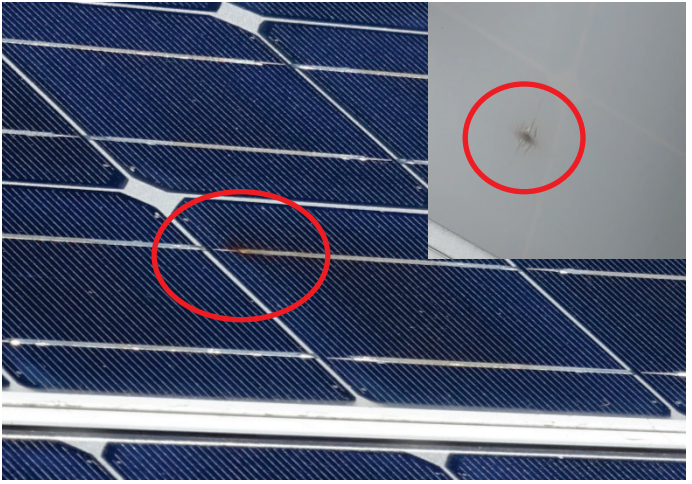
Encapsulant discoloration shows linear decline below 0.5 %/year, dominated by Isc losses.

Smith et al., WREF 2012

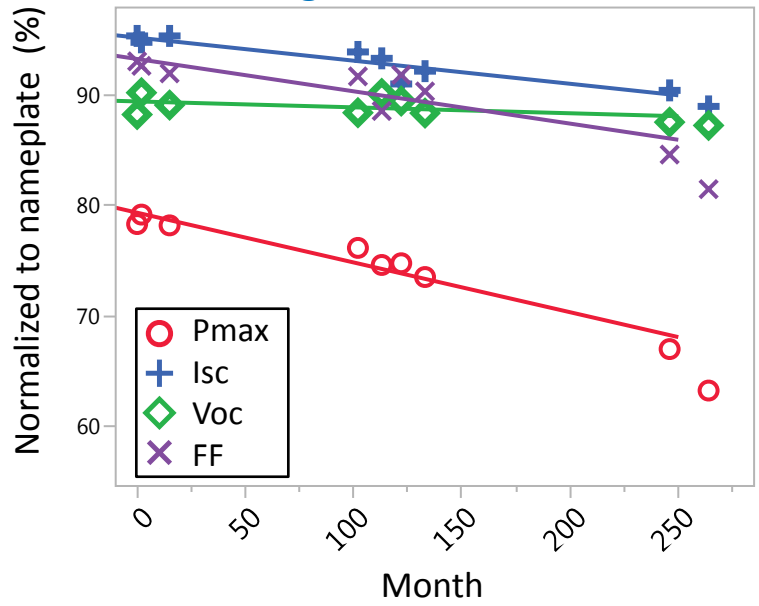
Hot-spots lead to larger power loss & pose safety issue



Internal circuitry (IC) failure due to solder bond



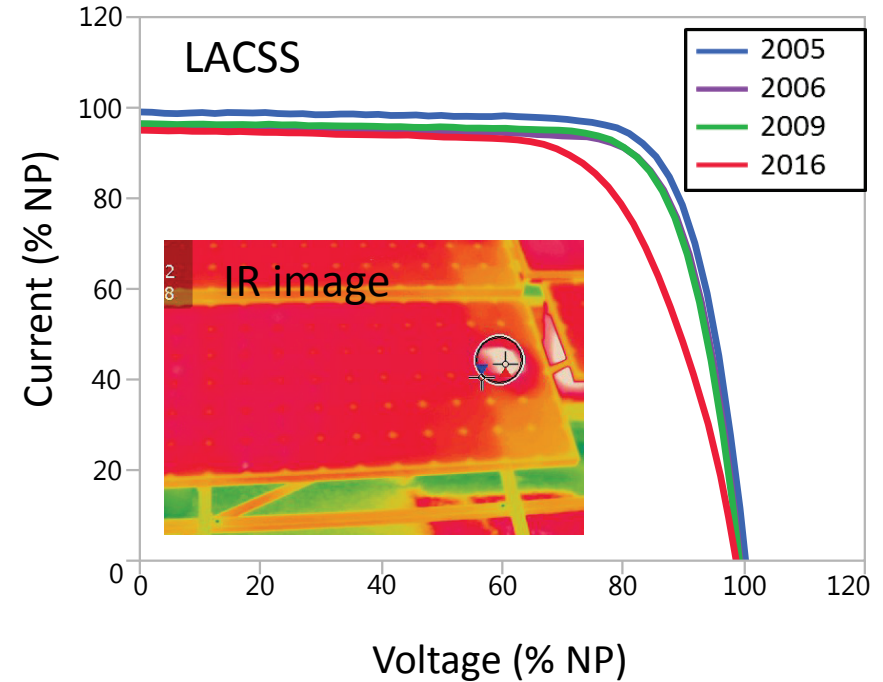
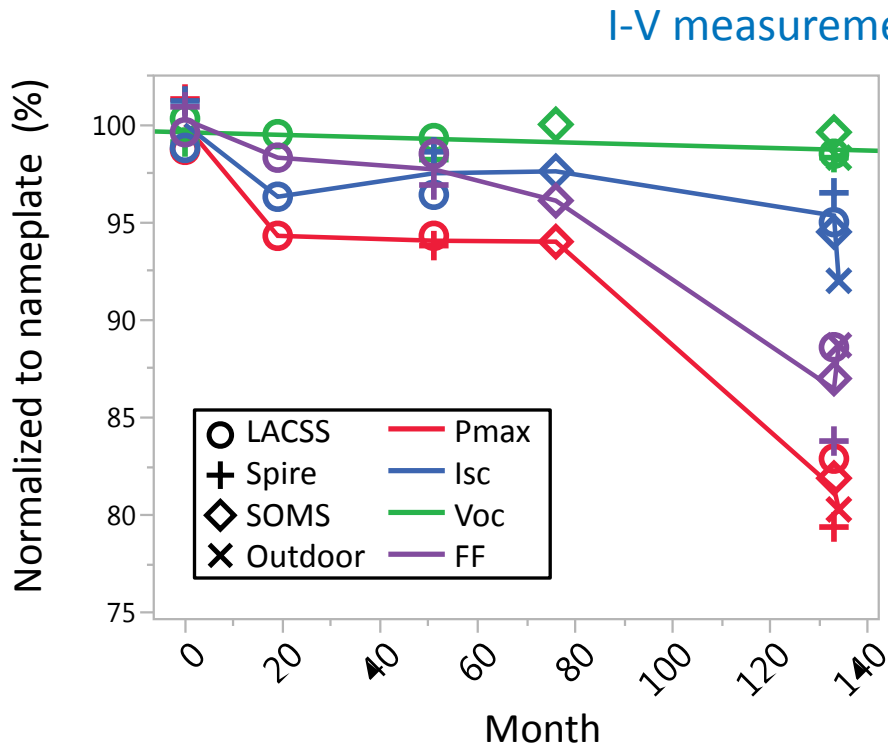
String IV measurements



The first 20 years decline appears to be around 0.5 %/year.

More rapid decline associated with FF loss.

Hot spot because of cracked cell causing non-linearity



LACSS: large area solar simulator

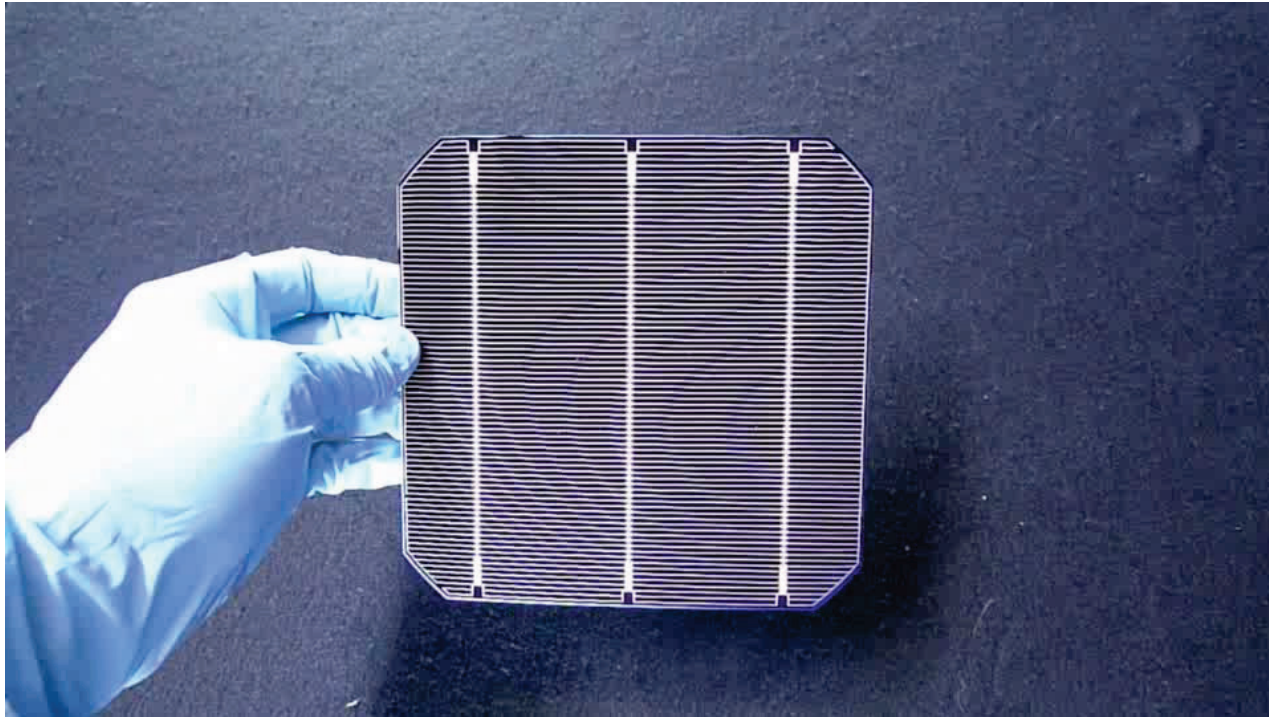
Spire: indoor flash tester

SOMS: standard outdoor measurement system

Outdoor: Daystar field measurements

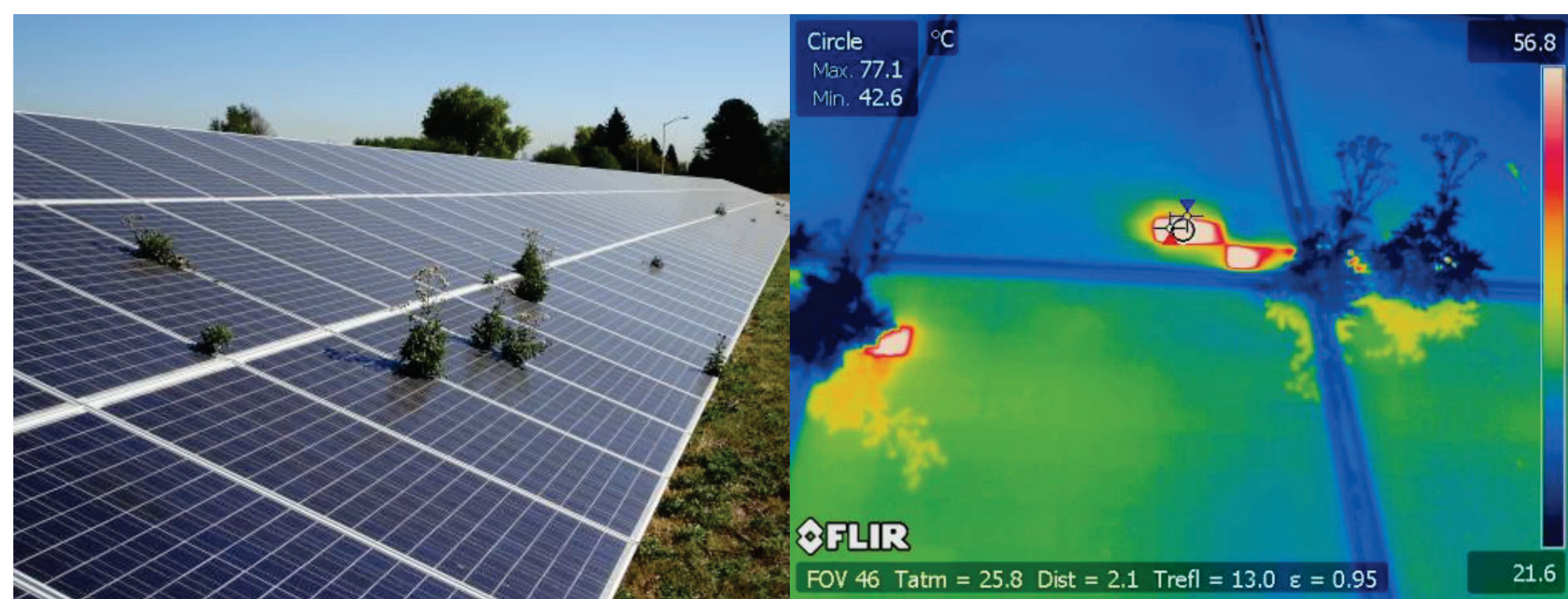
- ❖ Module was stable for several years
- ❖ Now we see more precipitous decline associated with FF losses, R_s increase

Cracked cells can easily be induced



<https://www.youtube.com/watch?v=-qdyxlybmoc>

Other reasons for hot spots

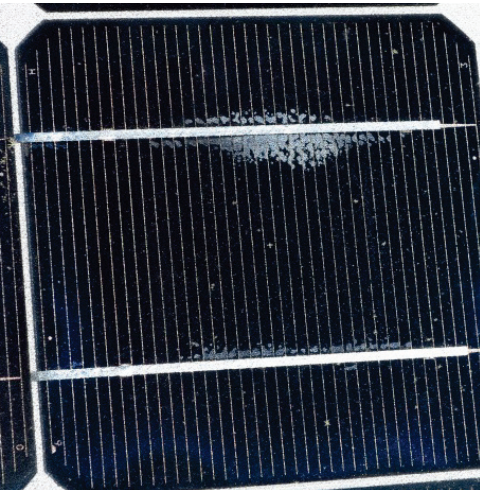


Constant shading stresses bypass diodes and may eventually lead to diode failure

Delamination can have different impact

Initial stages

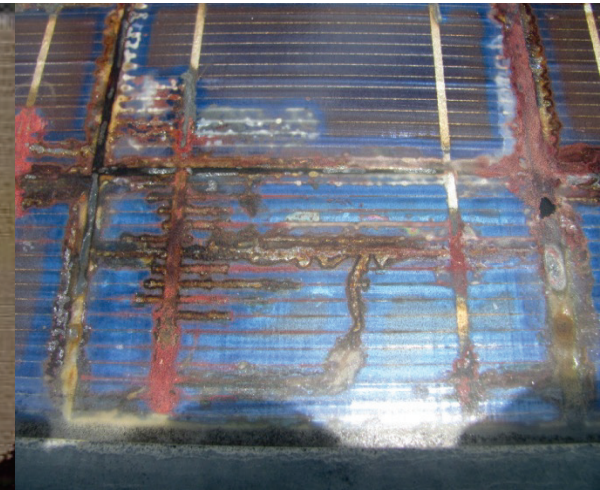
Encapsulant/Si



Glass/encapsulant

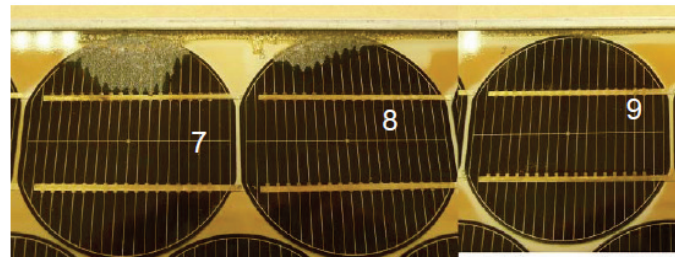
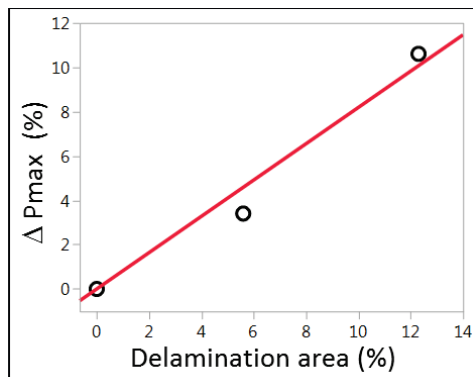


More advanced stages



Skoczek et al., *Progress in PV*, 2009

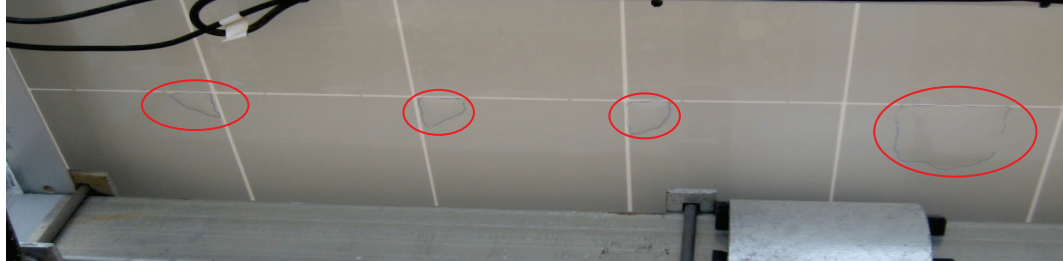
Before moisture ingress & corrosion delamination appears to scale with affected area, dominated by I_{sc} losses



Friesen et al., *PVMR*, 2011

Backsheet issues can have different impact

Minor issues



deGraaff et al. , PVMR, 2011

Major problem

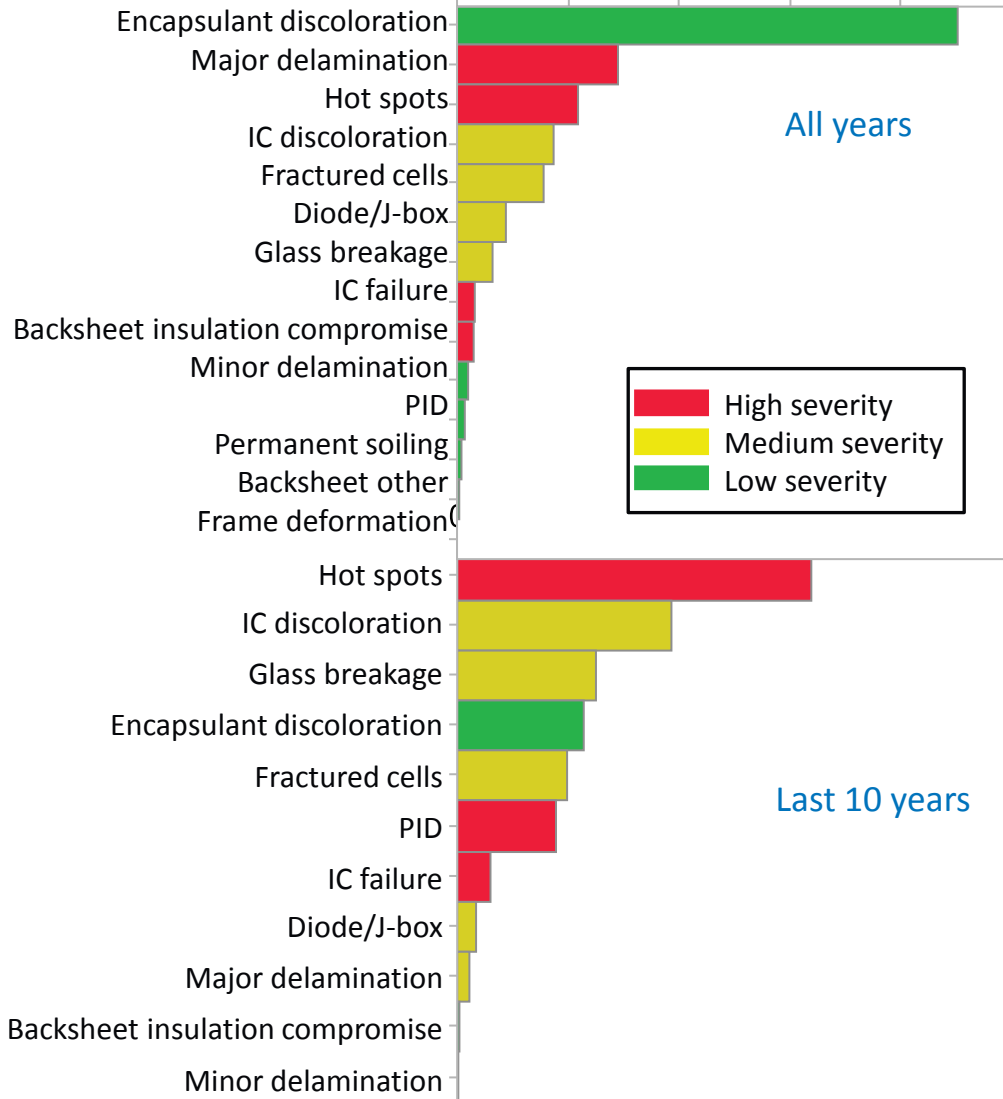


Mani et al. , PVSC, 2014

Hot-spots most common degradation mode in recent years

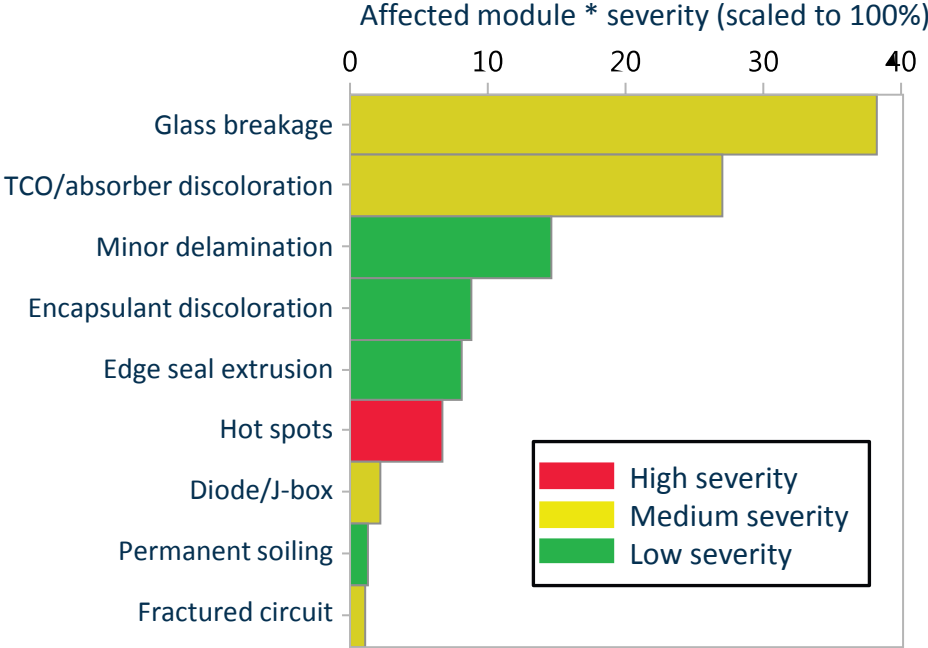
Affected module * severity (scaled to 100%)

0 10 20 30 40



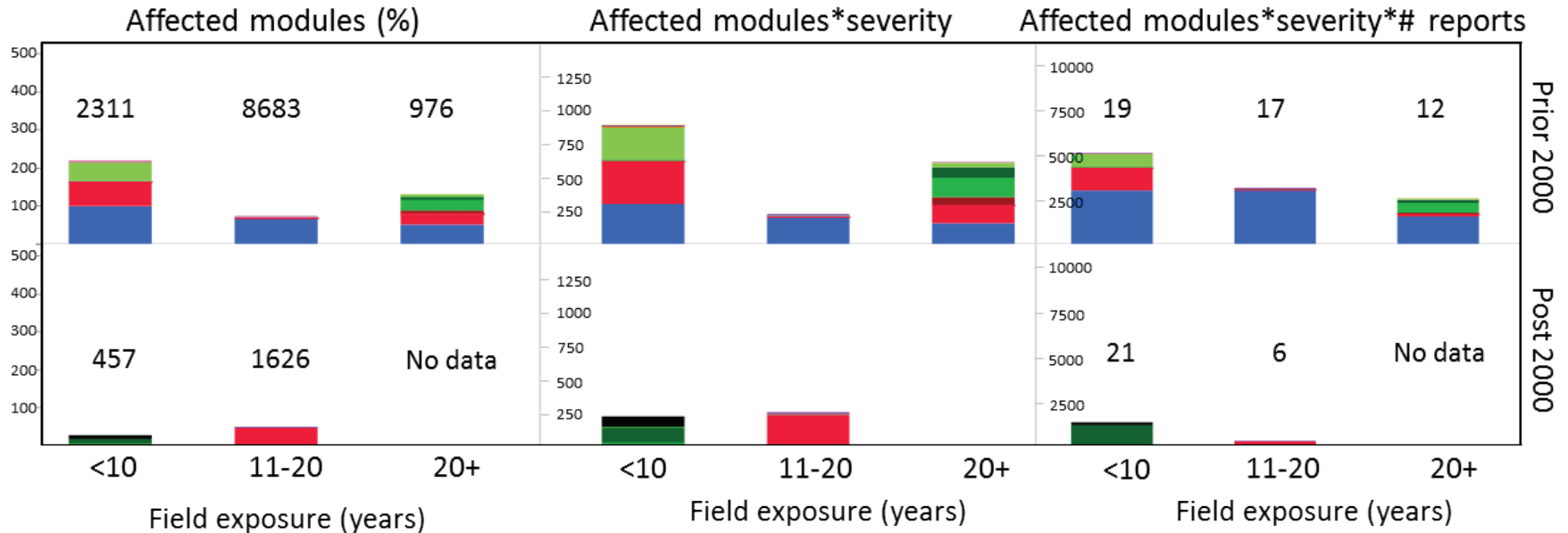
Thin-films: glass breakage most important

Don't have a lot of data on thin-film degradation modes

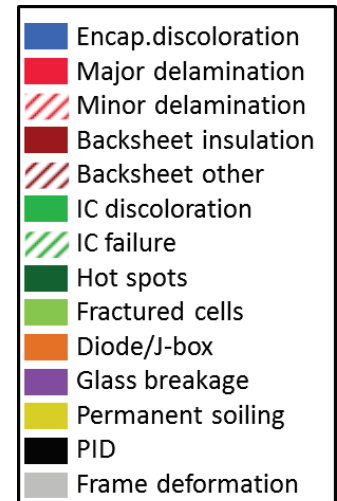


Percent of affected modules has gone down in newer installations

Moderate Climate

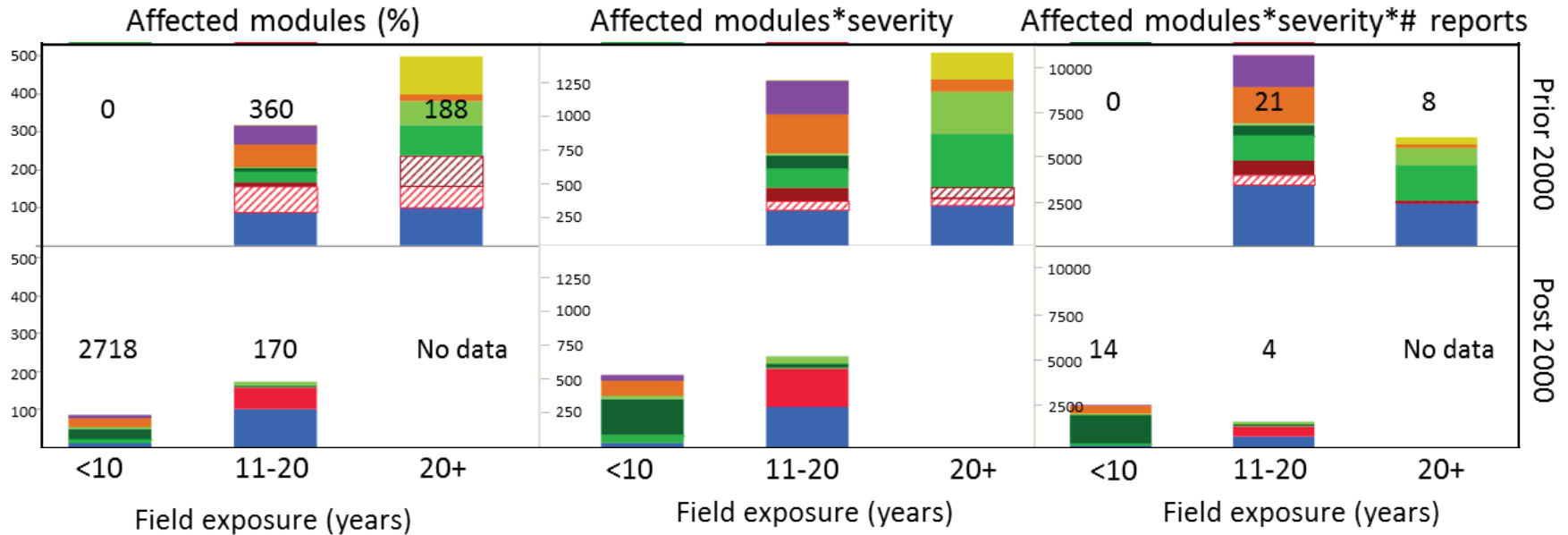


- ❖ Older installations, less than 10 field exposure dominated by pre-Block V modules
- ❖ Older installations: encapsulant discoloration dominant but absent in newer installations
- ❖ Percent of affected modules has gone down and changed.
- ❖ Hot spots & PID, and with more field exposure major delamination

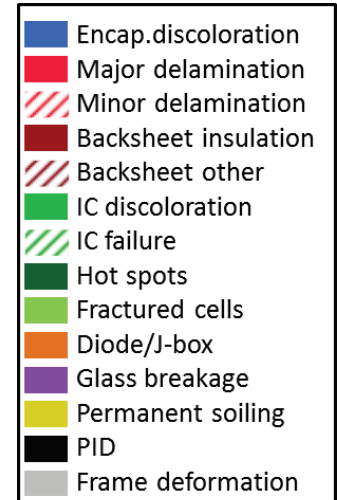


Hot & humid see higher fraction of modules affected

Hot & humid climate

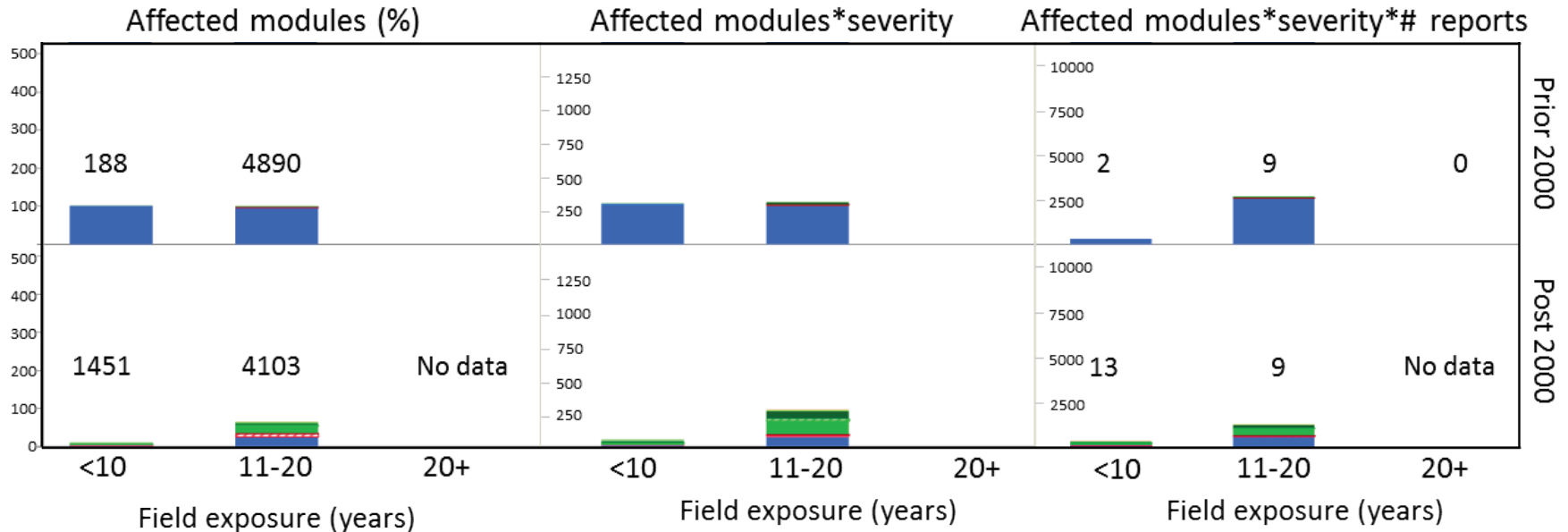


- ❖ Hot & humid climate more mix of degradation modes.
- ❖ Newer installations: hot spots, J-box issues
- ❖ For longer exposure major delamination appears
- ❖ Encapsulant discoloration still showing up in newer installations

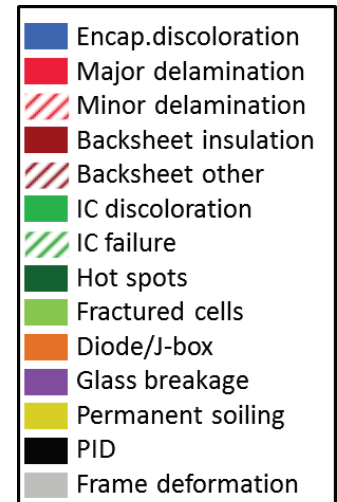


Desert, new installations: hot spots & internal circuitry discoloration

Desert climate

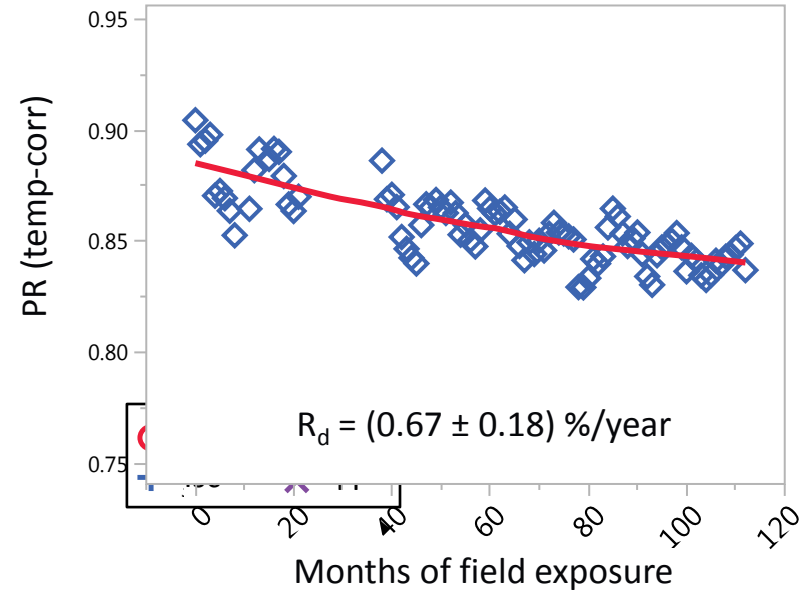


- ❖ Older installations: encapsulant discoloration
- ❖ Newer installations: hot spots & internal circuitry discoloration
- ❖ Encapsulant discoloration still showing up in newer installations

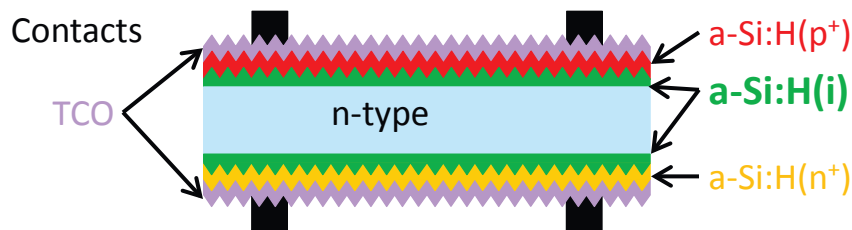


“New” Degradation Mode?

HIT (heterojunction with intrinsic thin layer)

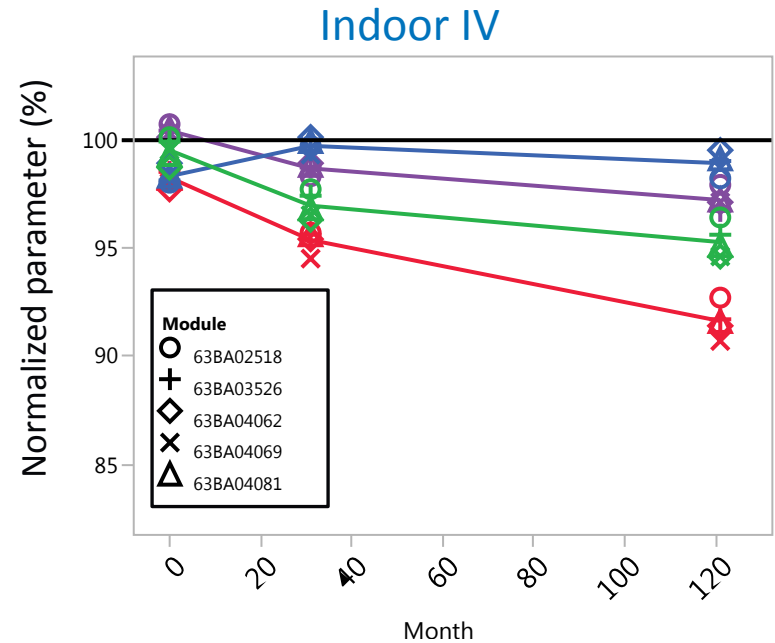
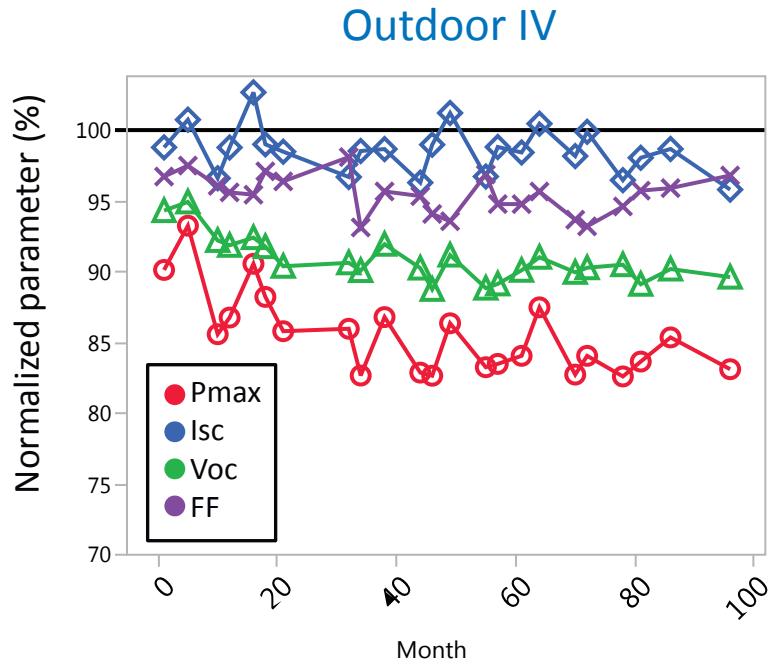


HIT



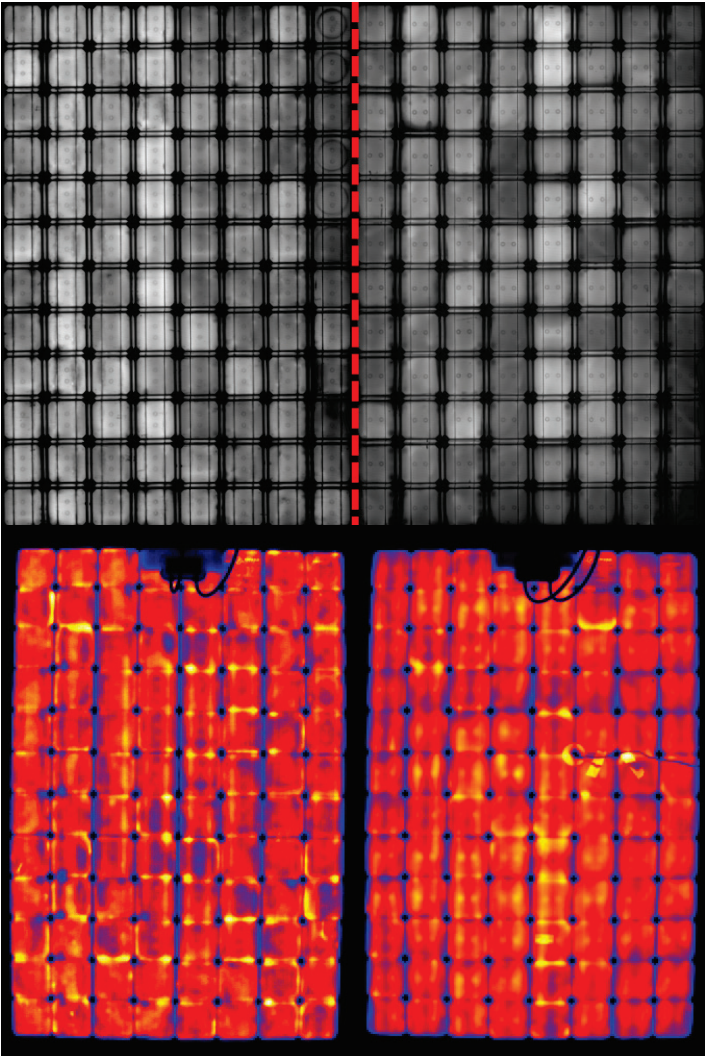
- System size: 1kW, 5 modules
- Installed Sep. 2007
- Kept control module indoors
- **Degradation is within warranty**

Nonlinear decline in Voc



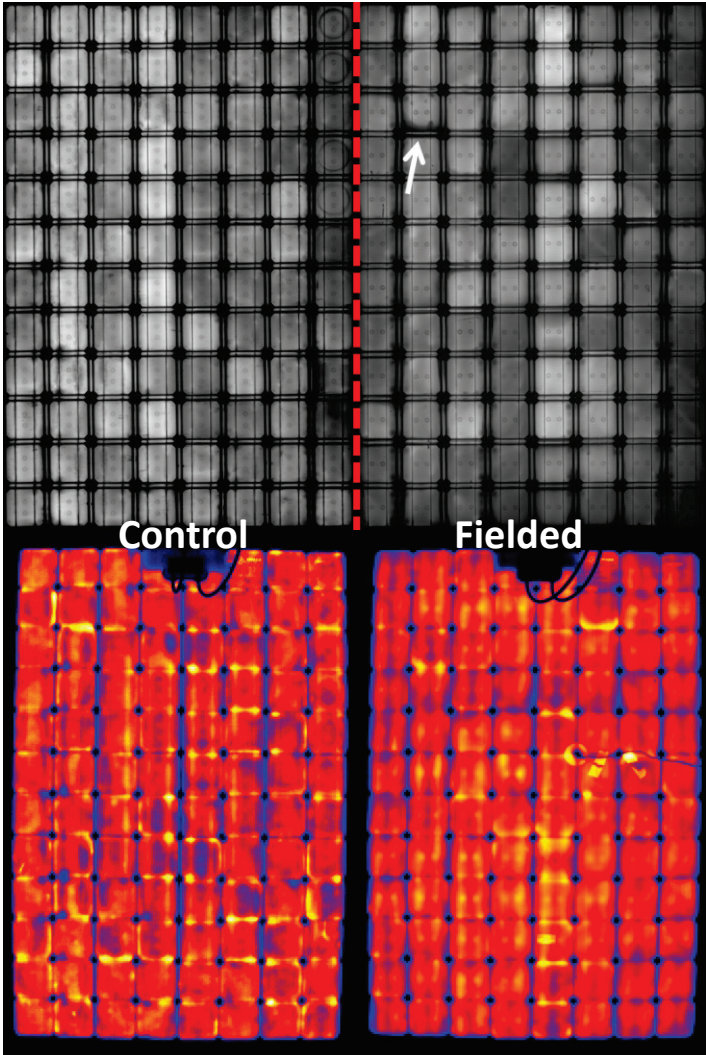
Isc: within measurement uncertainty
FF: small decrease
Voc: most of the decline in first 2 years

Electroluminescence



Dark Lock-in Thermography

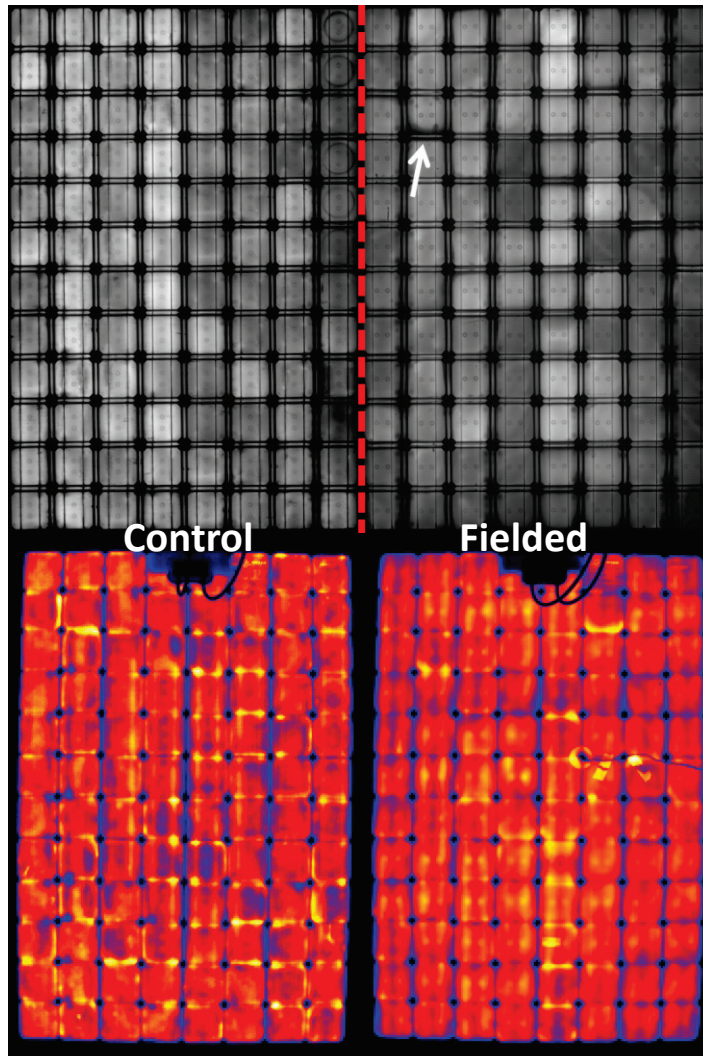
Electroluminescence



Dark Lock-in Thermography

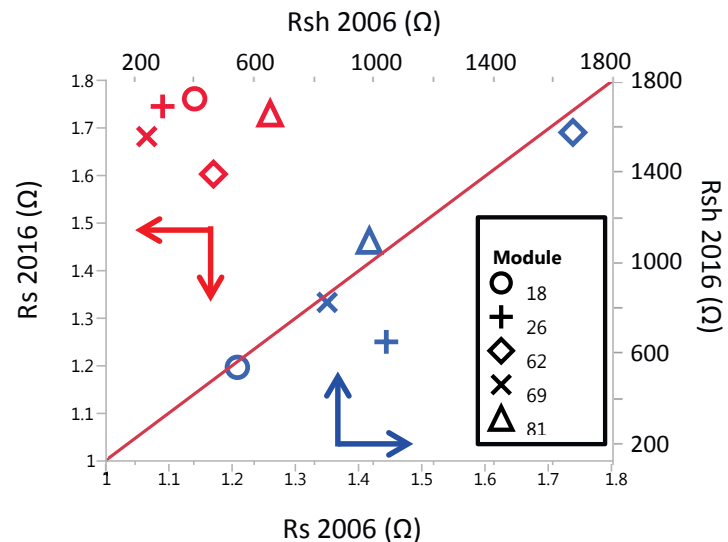
Uniform across module, R_s increase

Electroluminescence



Some cells show slight edge-shunting, but.. it is also present in the control module!

Dark IV taken in 2006 & 2016

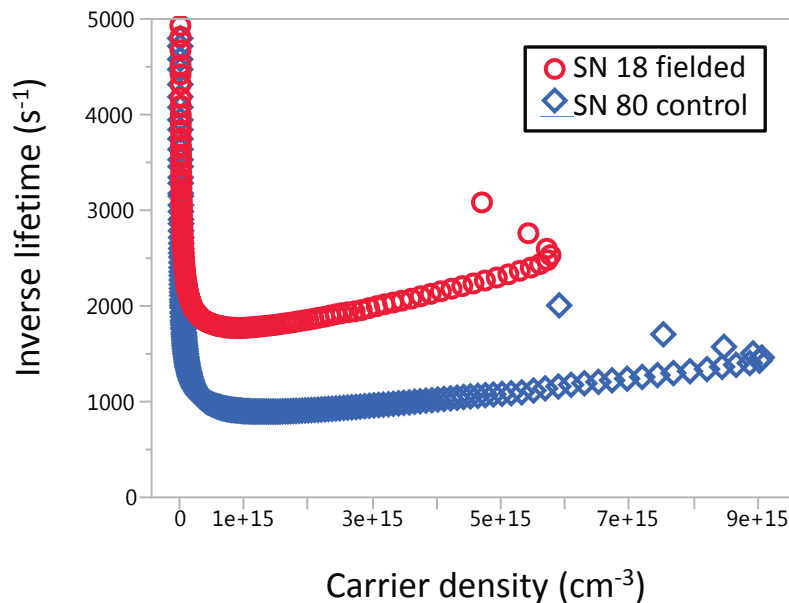


Some series resistance increase
No shunt resistance decrease

Dark Lock-in Thermography

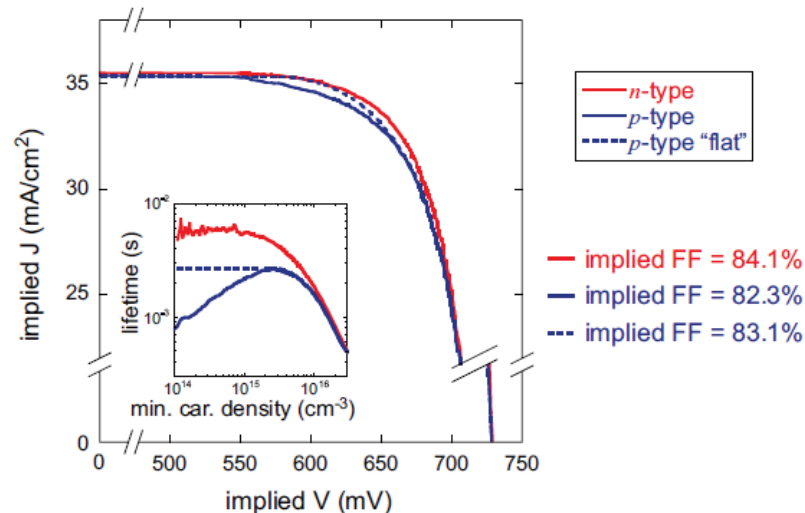
New cell designs may lead to “new” degradation modes

From Suns-Voc measurements



Sinton et al., EU PVSEC, 2000.

Same HIT structure on n- & p-type



Descoedres, De Wolf et al., JPV, 2013.

p-type lower FF \rightarrow lower quality passivation layer
Appears as a slightly “higher series resistance”

Passivation layer is degrading

Cell structure has changed with field exposure

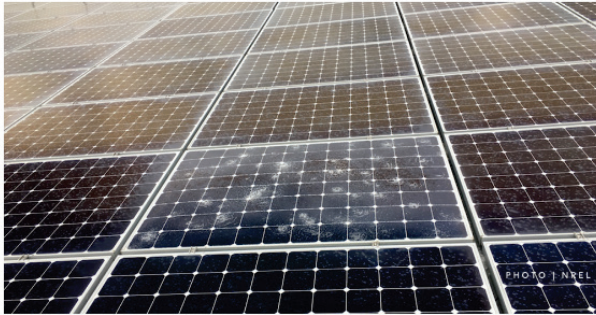
1. Prices go down \rightarrow new bill of materials leads to question on dependability
2. Efficiencies go up \rightarrow new cell designs may lead to “new” degradation modes

Modules fairly robust even in severe storms

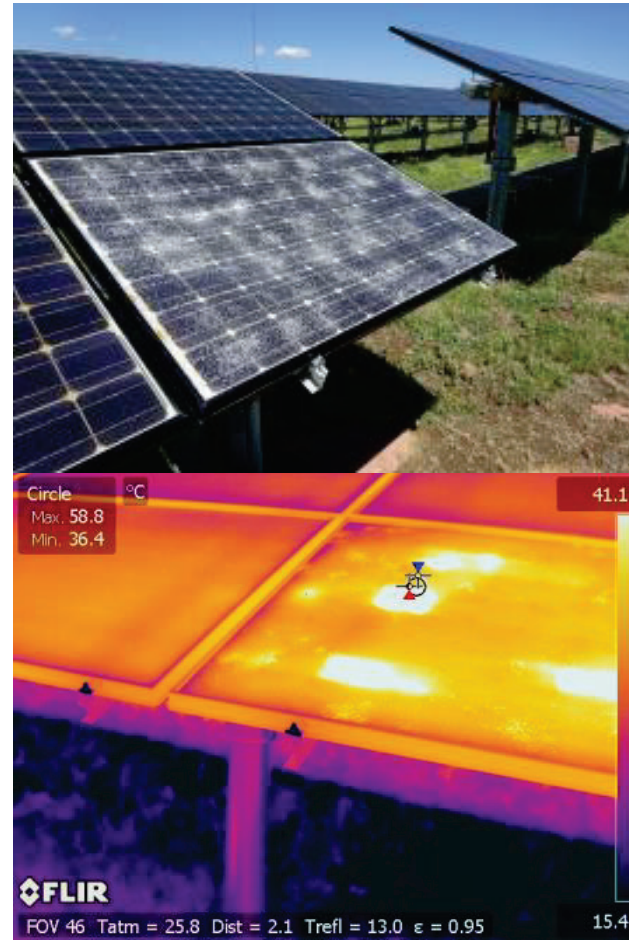
10 modules out of 3790, 8 year field exposure

→ failure rate $\lambda = 0.03 \text{ \%/year}$

Hail No! National Lab's Solar Panels Survive Severe Storm



Just one PV panel out of more than 3,000 was damaged at NREL following the hailstorm. Photo | NREL



Summary

- ❖ Failure rates are not often reported but mostly relatively low ca. 5 out of 10,000 annually
- ❖ Fewer degradation modes in newer installations
- ❖ Most dominant degradation modes in the last 10 years is hot-spots
- ❖ Change of bill of materials may lead to occurrence of new of old degradation modes
- ❖ Evolution of cell designs may lead to “new” degradation modes

Acknowledgments

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